

<b>Notice of References Cited</b>	Application/Control No. 09/924,926	Applicant(s)/Patent Under Reexamination SAID, AMIR	
	Examiner Fred Ferris	Art Unit 2128	Page 1 of 1

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*	B	US-5,891,394 A	04-1999	Drocourt et al.	422/50
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*	D	US-6,449,384 B2	09-2002	Laumeyer et al.	382/104
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"Statistical Pattern Recognition", A. Webb, Chapter 1, pp. 1-31, Oxford University Press, 1999 teaches statistical analysis in pattern recognition.
	V	"Robust Mesh Watermarking", Praun et al, ACM 1999
	W	"Statistical cues for Domain Specific Image Segmentation with Performance Analysis", Konishi et al, IEEE 1063-6919/00, 2000 IEEE
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.